

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
Ryan Lepisto		2883		

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*	B	US-4,569,569	02-1986	Stewart, William J.	385/36
*	C	US-2003/0081885	05-2003	Chen et al.	385/18
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	L	US-			
	M	US-			

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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